

MOSFET DATA : $\mu_n W/L = 1.2 \times 10^4 \text{ cm}^2 \text{ V}^{-1} \text{ s}^{-1}$
 $C_{ox} = 3.98 \times 10^{-8} \text{ F/cm}^2$ (87 nm oxide)
 $N_a = 2 \times 10^{16} \text{ cm}^{-3}$ $V_{FB} = -0.5 \text{ V}$

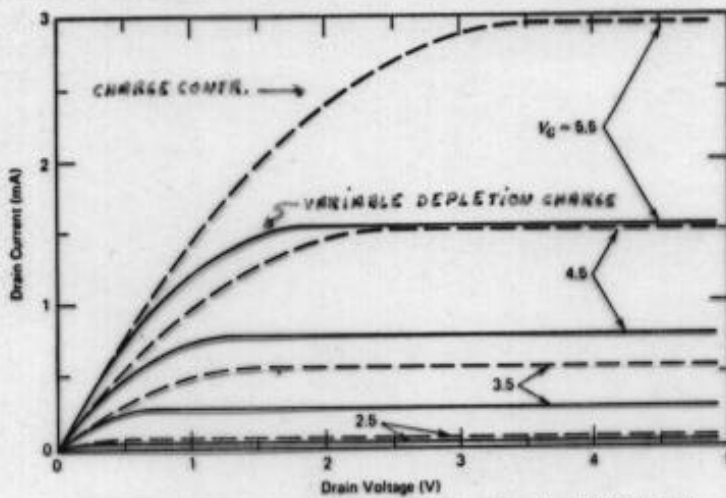


Figure 9.7 Theoretical predictions of I_D versus V_D using Equations 9.1.16 (dashed curves) and 9.1.15 (solid curves) for MOSFET having parameters given in the text. (I_D is taken to be equal to I_{Dsat} for $V_D > V_{Dsat}$.)

$$\left. \begin{array}{l} V_S = V_B = 0 \end{array} \right\}$$

CHARGE CONTROL

$$I_{D1} = \mu_n \frac{W}{L} \left[C_{ox} \left(V_G - V_{FB} - 2|\phi_p| - \frac{1}{2} V_D \right) \sqrt{2\epsilon_s q N_a |\phi_p|} \right]$$

VARIABLE DEPLETION-CHARGE

$$I_{D2} = \mu_n \frac{W}{L} \left\{ C_{ox} \left(V_G - V_{FB} - 2|\phi_p| - \frac{1}{2} V_D \right) V_D - \frac{2}{3} \sqrt{2\epsilon_s q N_a} \left[(2|\phi_p| + V_D)^{3/2} - (2|\phi_p|)^{3/2} \right] \right\}$$

EQUATIONS FOR CIRCUIT ANALYSIS

$$I_{DSAT}^{CC} > I_{DSAT}^{VDC}$$

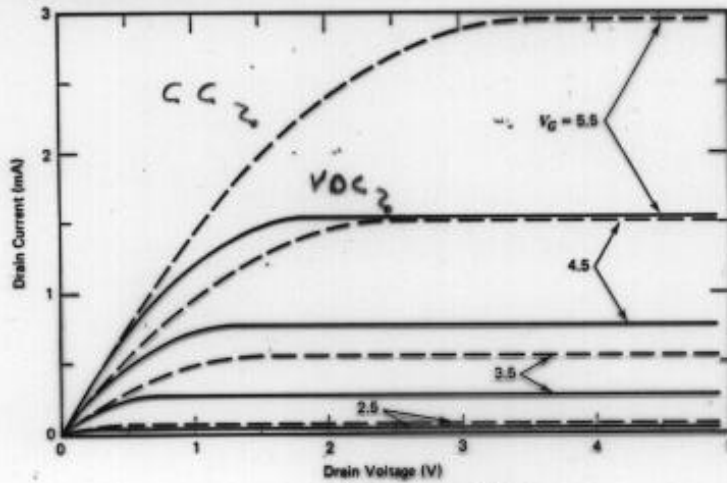
↑ SIMPLE
↑ ACCURATE
↓ TO BE DETERMINED

$$(NLNEQ) I_{DSAT}^{VDC} = k \frac{W}{2L} (V_G - V_T)^2 = \frac{k}{2} (V_G - V_T)^2 \quad (9.1.17)$$

C-C EXPRESSION

$$I_D = k \left[(V_G - V_T) V_{DS} - \frac{V_{DS}^2}{2} \right]$$

NEW PREFACTOR



V_G (V)	$V_G = 5.5$	
	V_{DS2} (V)	I_{DS2} (mA)
5.5	1.94	1.55
4.5	1.34	0.77
3.5	0.77	0.27
2.5	0.25	0.03

To obtain $k/2$ we must calculate V_T . By applying Equation 8.3.18, we find $V_T = 1.98$ V. We then use Equation 9.1.17 to write

$$\frac{k}{2} = \frac{I_{DS2}}{(V_G - V_T)^2} = \frac{1.55 \times 10^{-3}}{(5.5 - 1.98)^2} = 1.25 \times 10^{-4} \text{ AV}^{-2}$$

Using this value of $k/2$ in Equation 9.1.17 at the other gate biases, we find

V_G (V)	I_{DS2} (mA)	} NEW VALUES FROM MODIFIED C-C ANALYSIS.
5.5	1.55	
4.5	0.79	
3.5	0.29	
2.5	0.03	